

TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

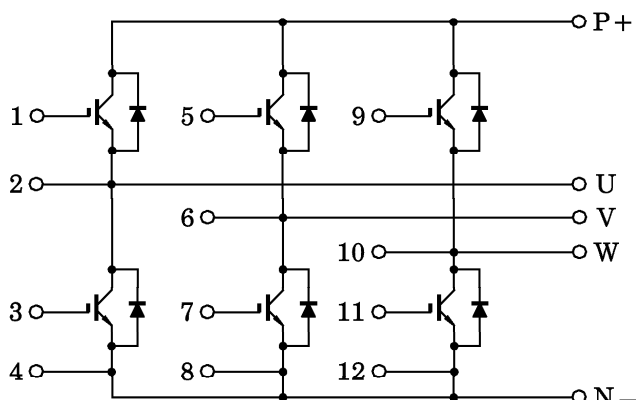
MG25Q6ES50A

HIGH POWER SWITCHING APPLICATIONS

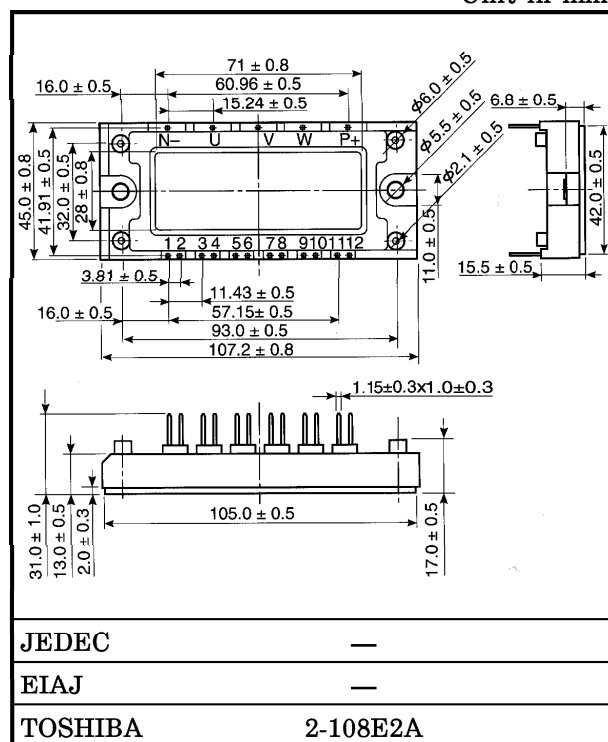
MOTOR CONTROL APPLICATIONS

- The Electrodes are Isolated from Case.
- High Input Impedance.
- 6 IGBTs Built Into 1 Package.

EQUIVALENT CIRCUIT



Unit in mm



Weight : 185g

961001EAA1

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MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Emitter Voltage		V _{CES}	1200	V
Gate-Emitter Voltage		V _{GES}	± 20	V
Collector Current	DC	I _C (25°C / 80°C)	35 / 25	A
	1ms	I _{CP} (25°C / 80°C)	70 / 50	A
Forward Current	DC	I _F	25	A
	1ms	I _{FM}	50	A
Collector Power Dissipation (T _c = 25°C)		P _C	200	W
Junction Temperature		T _j	150	°C
Storage Temperature Range		T _{stg}	− 40~125	°C
Isolation Voltage		V _{Isol}	2500 (AC 1 minute)	V
Screw Torque		—	6	N·m

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I _{GES}	V _{GE} = ± 20V, V _{CE} = 0	—	—	± 500	nA
Collector Cut-Off Current		I _{CES}	V _{CE} = 1200V, V _{GE} = 0	—	—	0.5	mA
Gate-Emitter Cut-Off Voltage		V _{GE (off)}	I _C = 25mA, V _{CE} = 5V	3.0	—	6.0	V
Collector-Emitter Saturation Voltage		V _{CE (sat)}	I _C = 25A, V _{GE} = 15V	—	2.8	3.2	V
			T _j = 125°C	—	3.1	3.7	
Input Capacitance		C _{ies}	V _{CE} = 10V, V _{GE} = 0, f = 1MHz	—	2600	—	pF
Switching Time	Rise Time	t _r	V _{CC} = 600V I _C = 25A, V _{GE} = ± 15V R _G = 51Ω, T _j = 125°C (Note 1)	—	0.07	0.15	μs
	Turn-On Time	t _{on}		—	0.15	0.30	
	Fall Time	t _f		—	0.07	0.10	
	Turn-Off Time	t _{off}		—	0.60	0.90	
Forward Voltage		V _F	I _F = 25A, V _{GE} = 0	—	2.0	2.8	V
Reverse Recovery Time		t _{rr}	I _F = 25A, V _{GE} = − 10V di / dt = 400A / μs (Note 1)	—	0.10	0.25	μs
Thermal Resistance		R _{th (j-c)}	Transistor Stage	—	—	0.6	°C / W
			Diode Stage	—	—	1.0	

(Note 1) Switching Time and Reverse Recovery Time Test Circuit & Timing Chart

